

Electronic Patent Application Fee Transmittal

Application Number:	10773524			
Filing Date:	06-Feb-2004			
Title of Invention:	Defect inspection apparatus and defect inspection method			
First Named Inventor/Applicant Name:	Takashi Yoneyama			
Filer:	Leonard Holtz/Diane Hegstrom			
Attorney Docket Number:	04083/LH			
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Utility Filing Fees				
Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Basic Filing:				
Pages:				
Claims:				
Miscellaneous-Filing:				
Petition:				
Patent-Appeals-and-Interference:				
Post-Allowance-and-Post-Issuance:				
Extension-of-Time:				

Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Miscellaneous:				
Submission- Information Disclosure Stmt	1806	1	180	180
Total in USD (\$)				180